

<IGBT Modules>

CM100DY-13T

HIGH POWER SWITCHING USE INSULATED TYPE



APPLICATION

AC Motor Control, Motion/Servo Control, Power supply, etc.

- **OPTION** (Below options are available.)
- •PC-TIM (Phase Change Thermal Interface Material) pre-apply

OUTLINE DRAWING & INTERNAL CONNECTION

Collector current Ic 100A Collector-emitter voltage VCES 6 5 0 V Maximum junction temperature T_{vimax} 175°C dual switch (half-bridge) •Copper base plate (Nickel-plating) Nickel-plating tab terminals • RoHS Directive compliant

•UL Recognized under UL1557, File No. E323585



MAXIMUM RATINGS (T_{vj}=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit
V _{CES}	Collector-emitter voltage	G-E short-circuited	650	V
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V
lc		DC, T _C =143 °C* (Note2, 4)	100	•
	Collector current	Pulse, Repetitive (Note3)	200	A
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	775	W
IE (Note1)		DC (Note2)	100	•
IERM (Note1)	Emitter current	Pulse, Repetitive (Note3)	200	A
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V
T _{vjmax}	Maximum junction temperature	Instantaneous event (overload)	175	°C
T _{Cmax}	Maximum case temperature (Note4)		150*	
Tvjop	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	*0
T _{stg}	Storage temperature	-	-40 ~ +150*	°C

ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	ltom	ltom Conditions		Limits			Linit
Symbol	Item Conditions		Min.	Тур.	Max.	Unit	
I _{CES}	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	1.0	mA
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited		-	-	0.5	μA
V _{GE(th)}	Gate-emitter threshold voltage	I _C =10 mA, V _{CE} =10 V		5.4	6.0	6.6	V
		I _C =100 A, V _{GE} =15 V,	T _{vj} =25 °C	-	1.35	1.65	v
V _{CEsat}		Refer to the figure of test circuit	T _{vj} =125 °C	-	1.45	-	
(Terminal)		(Note5)	T _{vj} =150 °C	-	1.50	-	
	Collector-emitter saturation voltage	I _C =100 A,	T _{vj} =25 °C	-	1.30	1.55	v
V _{CEsat}		V _{GE} =15 V,	T _{vj} =125 °C	-	1.35	-	
(Chip)		(Note5)	T _{vj} =150 °C	-	1.35	-	
Cies	Input capacitance	V _{CE} =10 V, G-E short-circuited		-	-	13.4	nF
Coes	Output capacitance			-	-	0.6	
Cres	Reverse transfer capacitance			-	-	0.3	1
Q _G	Gate charge	V _{CC} =300 V, I _C =100 A, V _{GE} =15 V		-	0.41	-	μC
t _{d(on)}	Turn-on delay time	- Vcc=300 V, Ic=100 A, VgE=±15 V,		-	-	200	- ns
t _r	Rise time			-	-	150	
t _{d(off)}	Turn-off delay time			-	-	400	
t _f	Fall time	$-R_{G}=6.2 \Omega$, Inductive load		-	-	400	
(Note 1)		I _E =100 A, G-E short-circuited,	T _{vj} =25 °C	-	2.05	2.85	1
V _{EC} (Note.1)		Refer to the figure of test circuit	T _{vj} =125 °C	-	1.95	- V	V
(Terminal)		(Note5)	T _{vj} =150 °C	-	1.95	-	
(Note 1)	 Emitter-collector voltage 	I _E =100 A,	T _{vj} =25 °C	-	1.90	2.65	
V _{EC} (Note.1)		G-E short-circuited,	T _{vj} =125 °C	-	1.80	-	V
(Chip)		(Note5)	T _{vj} =150 °C	-	1.80	-	
t _{rr} ^(Note1)	Reverse recovery time	V_{CC} =300 V, I _E =100 A, V _{GE} =±15 V,		-	-	150	ns
Qrr (Note1)	Reverse recovery charge	R_{G} =6.2 Ω , Inductive load		-	3.5	-	μC
Eon	Turn-on switching energy per pulse	$V_{CC}=300 \text{ V}, I_{C}=I_{E}=100 \text{ A},$ $V_{GE}=\pm 15 \text{ V}, R_{G}=6.2 \Omega, T_{vj}=150 \text{ °C},$		-	1.2	-	
E _{off}	Turn-off switching energy per pulse			-	5.1	-	mJ
Err (Note1)	Reverse recovery energy per pulse	Inductive load		-	1.8	-	mJ
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per switch, T _C =25 °C (Note4)		-	0.2	-	mΩ
r _g	Internal gate resistance	Per switch		-	0	-	Ω

*: The value of PC-TIM applied module is limited by the heat resistant temperature of PC-TIM.

THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
		Conditions	Min.	Тур.	Max.	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	193	K/kW
R _{th(j-c)D}	Thermai resistance	Junction to case, per Inverter FWD (Note4)	-	-	304	r/kvv
R _{th(c-s)}	Contact thermal resistance	Case to heat sink, per 1 module Thermal grease applied (Note4, 6)	-	36.6	-	K/kW

MECHANICAL CHARACTERISTICS

Symbol	ltam Con				Limits		
	Item	Conditions		Min.	Тур.	Max.	Unit
Mt	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		18.4	-	-	mm
		Terminal to base plate		21.1	-	-	
d	Clearance	Terminal to terminal		9.6	-	-	~~~
da	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline (Note7)		±0	-	+200	μm
m	mass	-		-	120	-	g

*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

2. Junction temperature $(T_{\nu j})$ should not increase beyond $T_{\nu j\,m\,a\,x}$ rating.

3. Pulse width and repetition rate should be such that the device junction temperature (T_{vj}) dose not exceed T_{vjmax} rating.

4. Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.

6. Typical value is measured by using thermally conductive grease of λ =3.0 W/(m·K)/D_(C-S)=50 µm.

7. The base plate (mounting side) flatness measurement point is as follows of the following figure.



RECOMMENDED OPERATING CONDITIONS

Symbol	Item	Conditions	Limits			Unit
	nem	Conditions	Min.	Тур.	Max.	Unit
V _{cc}	(DC) Supply voltage	Applied across C1-E2 terminals	-	300	450	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	6.2	-	62	Ω

CHIP LOCATION (Top view)

(94) (80)C2E1 E2 C1 (+)÷ **—** 3 **18.8**(Tr1) = N Ì 18.4(Di1) Tr1D 18.8(Tr2) (34) 2 17.0 18.5(Di2) i in **m** 5 ÷ 比 0 -Œ Ð Т đ ABEL SIDE ώ 4 'n. 7.0 64 0 29. 42. 57

Tr1/Tr2: IGBT, Di1/Di2: FWD

Option: PC-TIM applied baseplate outline



Dimension in mm, tolerance: ±1 mm

TEST CIRCUIT AND WAVEFORMS





Switching characteristics test circuit and waveforms

trr, Qrr characteristics test waveform







FWD Reverse recovery energy

Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

TEST CIRCUIT



PERFORMANCE CURVES



COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)





FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)



PERFORMANCE CURVES



(TYPICAL) V_{CC}=300 V, V_{GE}=±15 V, I_C=100 A, INDUCTIVE LOAD -: T_{vi}=150 °C, - - - -: T_{vj}=125 °C 10000 1000 (su) td(off) SWITCHING TIME t_{d(on} tf 100 t, 10 ò 20 30 40 50 10 60 70

HALF-BRIDGE SWITCHING CHARACTERISTICS

HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

EXTERNAL GATE RESISTANCE R_{G} (Ω)



PERFORMANCE CURVES



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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PERFORMANCE CURVES

TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)



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